National Semiconductor

DM54LS460A/DM74LS460A 10-Bit Comparator

General Description

The 'LS460A is a 10-bit comparator with true complement comparison status outputs. The device compares two 10-bit data strings (Ag−A0 and Bg−B0) to establish if this data is Equivalent (EQ=HIGH and NE=LOW) or Not Equivalent (EQ=LOW and NE=HIGH).

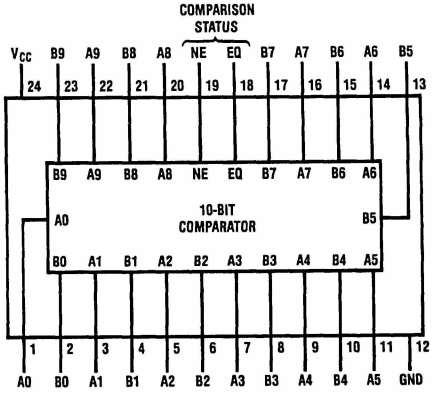
Outputs conform to the usual 8 mA LS totem-pole drive standard.

Features

- True and complement comparison status outputs
- 24-pin SKINNYDIP saves space
- Low current PNP inputs reduce loading
- Expandable in 10-bit increments
- 15 ns typical propagation delay

Connection Diagram

Top View



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Order Number DM54LS460AJ, DM74LS460AJ, DM74LS460AN or DM74LS460AV
See NS Package Number J24F, N24C or V28A

Function Table

A9−A0	B9−B0	EQ	NE	Operation
A	A	H	L	Equivalent (A=B)
B	B	H	L	
A	B	L	H	Not Equivalent (A≠B)

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V_{CC})	−0.5 to +7V (Note 2)
Input Voltage	−1.5 to +5.5V (Note 2)
Off-State Output Voltage	−1.5 to +5.5V (Note 2)
Input Current	−30.0 mA to +5.0 mA (Note 2)
Output Current (I_{OL})	+100 mA
Storage Temperature	−65°C to +150°C
Ambient Temperature with Power Applied	−65°C to +125°C
Junction Temperature with Power Applied	−65°C to +150°C
ESD Tolerance	2000V

CZAP = 100 pF
RZAP = 1500Ω
Test Method: Human Body Model
Test Specification: NSC SOP-5-028

Recommended Operating Conditions

Symbol	Parameter	Military			Commercial			Units
		Min	Nom	Max	Min	Nom	Max	
V_{CC}	Supply Voltage	4.5	5	5.5	4.75	5	5.25	V
T_A	Operating Free-Air Temperature	−55		125	0		75	°C

Electrical Characteristics Over Recommended Operating Conditions

Symbol	Parameter	Test Conditions			Min	Typ	Max	Units
V_{IL}	Low Level Input Voltage (Note 3)						0.8	V
V_{IH}	High Level Input Voltage (Note 3)				2			V
V_{IC}	Input Clamp Voltage	V_{CC} = Min, I = −18 mA					−1.5	V
I_{IL}	Low Level Input Current	V_{CC} = Max, VI = 0.4V					−0.25	mA
I_{IH}	High Level Input Current	V_{CC} = Max, VI = 2.4V					25	μA
I_I	Maximum Input Current	V_{CC} = Max, VI = 5.5V					1	mA
V_{OL}	Low Level Output Voltage	V_{CC} = Min	I_{OL} = 8 mA				0.5	V
V_{OH}	High Level Output Voltage	V_{CC} = Min	I_{OH} = −2 mA	MIL	2.4			V
			I_{OH} = −3.2 mA	COM				
I_{OS}	Output Short-Circuit Current (Note 4)	V_{CC} = 5V, V_O = 0V			−30		−130	mA
I_{CC}	Supply Current	V_{CC} = Max, Outputs Open				60	100	mA

Note 1: Absolute maximum ratings are those values beyond which the device may be permanently damaged. Proper operation is not guaranteed outside the specified recommended operating conditions.

Note 2: Some device pins may be raised above these limits during programming operations according to the applicable specification.

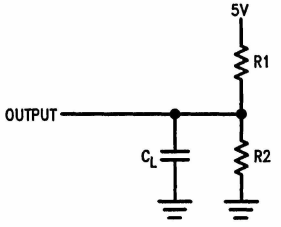
Note 3: These are absolute voltages with respect to the ground pin on the device and include all overshoots due to system and/or tester noise. Do not attempt to test these values without suitable equipment.

Note 4: To avoid invalid readings in other parameter tests, it is preferable to conduct the I_{OS} test last. To minimize internal heating, only one output should be shorted at a time with a maximum duration of 1.0 second each. Prolonged shorting of a high output may raise the chip temperature above normal and permanent damage may result.

Switching Characteristics Over Recommended Operating Conditions

Symbol	Parameter	Test Conditions	Military			Commercial			Units
			Min	Typ	Max	Min	Typ	Max	
T_{pd}	Input to Output	C_L = 50 pF			35			30	ns

Test Load



MIL/COM
R1 = 560
R2 = 1.1k

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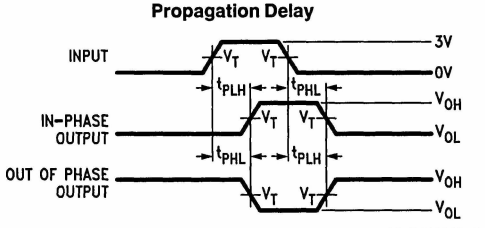
Test Waveform



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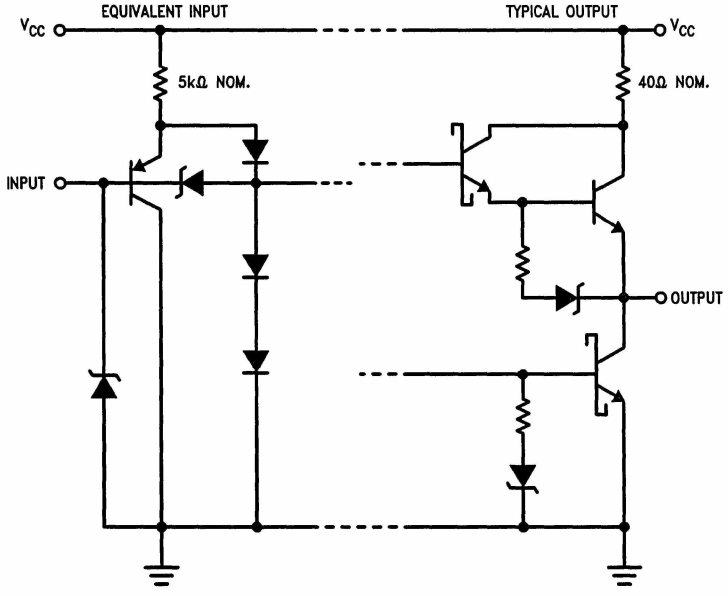
Notes:

V_T = 1.5V

C_L includes probe and jig capacitance.

In the examples above, the phase relationships between inputs and outputs have been chosen arbitrarily.

Schematic of Inputs and Outputs



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Logic Diagram